



8-CHANNEL, 12-/10-/8-BIT, 2.7-V TO 5.5-V LOW POWER DIGITAL-TO-ANALOG **CONVERTERS WITH POWER DOWN AND INTERNAL REFERENCE**

FEATURES

• Eight Voltage Output DACs in One Package

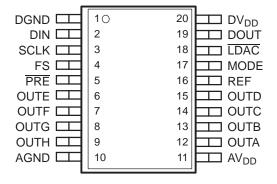
UMENTS

- TLV5630 ...12-Bit
- TLV5631 ... 10-Bit
- TLV5632 . . . 8-Bit
- 1 μs in Fast Mode
- 3 μs in Slow Mode
- **Programmable Settling Time vs Power** Consumption
 - 1 μs in Fast Mode
 - 3 us in Slow Mode
 - 18 mW in Slow Mode at 3 V
 - 48 mW in Fast Mode at 3 V
- Compatible With TMS320 and SPI Serial Ports
- **Monotonic Over Temperature**
- **Low Power Consumption:**
 - 18 mW in Slow Mode at 3 V
 - 48 mW in Fast Mode at 3 V
- **Power-Down Mode**
- **Internal Reference**
- **Data Output for Daisy-Chaining**

APPLICATIONS

- **Digital Servo Control Loops**
- **Digital Offset and Gain Adjustment**
- **Industrial Process Control**
- **Machine and Motion Control Devices**
- **Mass Storage Devices**

DW OR PW PACKAGE (TOP VIEW)



DESCRIPTION

The TLV5630, TLV5631, and TLV5632 are pin-compatible, eight-channel, 12-/10-/8-bit voltage output DACs each with a flexible serial interface. The serial interface allows glueless interface to TMS320 and SPI, QSPI, and Microwire serial ports. It is programmed with a 16-bit serial string containing 4 control and 12 data bits.

Additional features are a power-down mode, an LDAC input for simultaneous update of all eight DAC outputs, and a data output which can be used to cascade multiple devices, and an internal programmable band-gap reference.

The resistor string output voltage is buffered by a rail-to-rail output amplifier with a programmable settling time to allow the designer to optimize speed vs power dissipation. The buffered, high-impedance reference input can be connected to the supply voltage.

Implemented with a CMOS process, the DACs are designed for single-supply operation from 2.7 V to 5.5 V, and can operate on two separate analog and digital power supplies. The devices are available in 20-pin SOIC and TSSOP packages.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



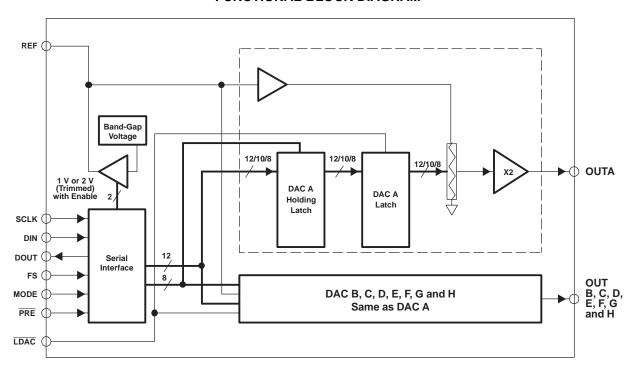


These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

AVAILABLE OPTIONS

| т. | PACKAGE | | | | | | | |
|--------------|------------|------------|------------|--|--|--|--|--|
| TA | SOIC (DW) | TSSOP (PW) | RESOLUTION | | | | | |
| | TLV5630IDW | TLV5630IPW | 12 | | | | | |
| 40°C to 85°C | TLV5631IDW | TLV5631IPW | 10 | | | | | |
| | TLV5632IDW | TLV5632IPW | 8 | | | | | |

FUNCTIONAL BLOCK DIAGRAM



Terminal Functions

| TERM | INAL | 1/0 | DESCRIPTION |
|-----------|------------|-----|---|
| NAME | NO. | 1/0 | DESCRIPTION |
| AGND | 10 | Р | Analog ground |
| AV_{DD} | 11 | Р | Analog power supply |
| DGND | 1 | Р | Digital ground |
| DIN | 2 | I | Digital serial data input |
| DOUT | 19 | 0 | Digital serial data output |
| DV_DD | 20 | Р | Digital power supply |
| FS | 4 | I | Frame sync input |
| LDAC | 18 | I | Load DAC. The DAC outputs are only updated, if this signal is low. It is an asynchronous input. |
| MODE | 17 | I | DSP/ μ C mode pin. High = μ C mode, NC = DSP mode. |
| PRE | 5 | I | Preset input |
| REF | 16 | I/O | Voltage reference input/output |
| SCLK | 3 | I | Serial clock input |
| OUTA-OUTH | 12-15, 6-9 | 0 | DAC outputs A, B, C, D, E, F, G and H |



ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature (unless otherwise noted) (1)

| | UNIT |
|--|-----------------------------------|
| Supply voltage, (AV _{DD} , DV _{DD} to GND) | 7 V |
| Reference input voltage range | - 0.3 V to AV _{DD} + 0.3 |
| Digital input voltage range | - 0.3 V to DV _{DD} + 0.3 |
| Operating free-air temperature range, T _A | -40°C to 85°C |
| Storage temperature range, T _{stg} | -65°C to 150°C |
| Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds | 260°C |

⁽¹⁾ Stresses beyond those listed under, absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under, recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

RECOMMENDED OPERATING CONDITIONS

| | | MIN | TYP | MAX | UNIT |
|---|--|-----|-------|-----------|------|
| Supply voltage AV DV | 5-V operation | 4.5 | 5 | 5.5 | V |
| Supply voltage, AV _{DD} , DV _{DD} | 3-V operation | 2.7 | 3 | 3.3 | V |
| High lovel digital input V | $DV_{DD} = 2.7 \text{ V}$ | 2 | | | V |
| High-level digital input, V _{IH} | $DV_{DD} = 5.5 \text{ V}$ | 2.4 | | | V |
| Low lovel digital input V | DV _{DD} = 2.7 V | | | 0.6 | V |
| Low-level digital input, V _{IL} | DV _{DD} = 5.5 V | | | 1.0 | V |
| Reference voltage, V _{ref} | AV _{DD} = 5 V, See ⁽¹⁾ | GND | 2.048 | AV_{DD} | V |
| Reference voltage, v _{ref} | $AV_{DD} = 3 \text{ V, See}^{(1)}$ | GND | 1.024 | AV_DD | V |
| Analog output load resistance, R _L | | 2 | | | kΩ |
| Analog output load capacitance, C _L | | | | 100 | pF |
| Clock frequency, f _{CLK} | | | | 30 | MHz |
| Operating free-air temperature, T _A | | -40 | | 85 | °C |

⁽¹⁾ Reference input voltages greater than AV_{DD}/2 causes saturation for large DAC codes.

ELECTRICAL CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

| | PARAMETER | TEST CONDITION | MIN TYP | MAX | UNIT | |
|-------|------------------------------|---|----------|-----|------|----|
| POWER | SUPPLY | | <u> </u> | | | |
| | Dower cumply current | No load, All inputs = DV _{DD} or GND, | Fast | 16 | 21 | A |
| IDD | Power supply current | No load, All inputs = DV_{DD} or GND, V_{ref} = 2.048 V, See $^{(1)}$ | Slow | 6 | 8 | mA |
| | Power-down supply current | | | 0.1 | | μΑ |
| POR | Power on threshold | | | 2 | | V |
| PSRR | Power supply rejection ratio | Full scale, See (2) | | -50 | | dB |

⁽¹⁾ I_{DD} is measured while continuously writing code 2048 to the DAC. For $V_{IH} < DV_{DD}$ - 0.7 V and $V_{IL} > 0.7$ V, supply current increases.

(2) Power supply rejection ratio at full scale is measured by varying AV_{DD} and is given by: PSRR = 20 log [(E_G(AV_{DD}max) - E_G(AV_{DD}min))/V_{DD}max]



ELECTRICAL CHARACTERISTICS (continued)

over recommended operating conditions (unless otherwise noted)

| | PARAMETER | | TEST CONDITI | IONS | | MIN | TYP | MAX | UNIT |
|--------------------------|--------------------------------------|--|-----------------------------|-----------|-----------------|------------|-------|-----------------------|------------------|
| STATIC DA | AC SPECIFICATIONS | | | | | | | | |
| | | TLV5630 | | | | | 12 | | Bits |
| | Resolution | TLV5631 | | | | | 10 | | Bits |
| | | TLV5632 | | | | | 8 | | Bits |
| | | TLV5630 | | (| Code 40 to 4095 | | ±2 | ±6 | LSB |
| INL | Integral nonlinearity | TLV5631 | V _{ref} = 1 V, 2 V | (| Code 20 to 1023 | | ±0.5 | ±2 | LSB |
| | | TLV5632 | | (| Code 6 to 255 | | ±0.3 | ±1 | LSB |
| | | TLV5630 | | (| Code 40 to 4095 | | ±0.5 | ±1 | LSB |
| DNL | Differential nonlinearity | TLV5631 | V _{ref} = 1 V, 2 V | (| Code 20 to 1023 | | ±0.1 | ±1 | LSB |
| | | TLV5632 | | (| Code 6 to 255 | | ±0.1 | ±1 | LSB |
| E _{ZS} | Zero scale error (offset e scale) | error at zero | | | | | | ±30 | mV |
| E _{ZS} TC | Zero scale error tempera coefficient | ature | | | | | 30 | | μV/°C |
| E_G | Gain error | | | | | | | ±0.6 | %Full Scale V |
| EGTC | Gain error temperature of | coefficient | | | | | 10 | | ppm/°C |
| OUTPUT S | SPECIFICATIONS | | | | | | | | |
| Vo | Voltage output range | $R_L = 10 \text{ k}\Omega$ | | | | 0 | | AV _{DD} -0.4 | V |
| | Output load regulation accuracy | $R_L = 2 k\Omega vs$ | 10 kΩ | | | | | ±0.3 | %Full Scale V |
| REFEREN | CE OUTPUT | | | | · | | | | |
| $V_{REFOUTL}$ | Low reference voltage | V _{DD} > 4.75 V | | | | 1.010 | 1.024 | 1.040 | V |
| $V_{REFOUTH}$ | High reference voltage | | | | | 2.020 | 2.048 | 2.096 | V |
| I _{ref(Source)} | Output source current | | | | | | | 1 | mA |
| I _{ref(Sink)} | Output sink current | | | | | -1 | | | mA |
| | Load capacitance | See (3) | | | | 1 | 10 | | μF |
| PSRR | Power supply rejection ratio | | | | | | 60 | | dB |
| REFEREN | CE INPUT | | | | | | | | |
| VI | Input voltage range | | | | | 0 | | AV_DD | V |
| R_I | Input resistance | | | | | | 50 | | kΩ |
| C _I | Input capacitance | | | | | | 10 | | pF |
| | Reference input bandwidth | V _{ref} = 0.4 V _{pp} Input code = | + 2.048 Vdc, 0x800 | Fast Slow | | 2.2 1.9 | | MHz MHz | |
| | Reference feedthrough | t 1 kHz + 2.048 Vdc, | | JIOW | | 84 | | dB | |
| DIGITAL IN | | rei – z vpp c | M 12 1 2.040 VUC, | 300 | | | 7 | | uD |
| I _{IH} | High-level digital input current | V _I = DV _{DD} | | | | | | 1 | μА |
| I _{IL} | Low-level digital input current | V _I = 0 V | 1 | | | μА | | | |
| C _I | Input capacitance | | | | | | 8 | | pF |

⁽³⁾ In parallel with a 100-nF capacitor

⁽⁴⁾ Reference feedthrough is measured at the DAC output with an input code = 0x000.



ELECTRICAL CHARACTERISTICS (continued)

over recommended operating conditions (unless otherwise noted)

| | PARAMETER | TEST CONDITION | IS | MIN | TYP | MAX | UNIT |
|--------------------|-----------------------------------|--|----------------|-----|-----|----------|------|
| DIGITAL | OUTPUT | | | - | | <u>.</u> | |
| V _{OH} | High-level digital output voltage | $R_L = 10 \text{ k}\Omega$ | | 2.6 | | | V |
| V _{OL} | Low-level digital output voltage | $R_L = 10 \text{ k}\Omega$ | | | 0.4 | V | |
| | Output voltage rise time | $R_L = 10 \text{ k}\Omega$, $C_L = 20 \text{ pF}$, Includes pro | pagation delay | | 5 | 10 | ns |
| ANALO | G OUTPUT DYNAMIC PERF | ORMANCE | | - | | <u>.</u> | |
| | Output settling time, full | $R_1 = 10 \text{ k}\Omega$, $C_1 = 100 \text{ pF}$, See ⁽⁵⁾ | Fast | | 1 | 3 | |
| t _{s(FS)} | scale | $R_L = 10 \text{ k}\Omega$, $C_L = 100 \text{ pr}$, See (3) | Slow | | 3 | 7 | μs |
| | Output settling time, | B 40 k0 C 400 pF Co. (6) | Fast | | 0.5 | 1 | |
| t _{s(CC)} | code to code | $R_L = 10 \text{ k}\Omega, C_L = 100 \text{ pF}, \text{ See }^{(6)}$ | Slow | | 1 | 2 | μs |
| CD | Class rate | B 40 k0 C 400 pF Cos (7) | Fast | 4 | 10 | | \//: |
| SR | Slew rate | $R_L = 10 \text{ k}\Omega, C_L = 100 \text{ pF}, \text{ See}^{(7)}$ | Slow | 1 | 3 | | V/μs |
| | Glitch energy | See ⁽⁸⁾ | · | | 4 | | nV-s |
| | Channel crosstalk | | | 90 | | dB | |

⁽⁵⁾ Settling time is the time for the output signal to remain within ±0.5 LSB of the final measured value for a digital input code change of 0x080 to 0xFFF and 0xFFF to 0x080, respectively. Assured by design; not tested.

DIGITAL INPUT TIMING REQUIREMENTS

| | PARAMETER | MIN | TYP | MAX | UNIT |
|-------------------------|---|--------------|-----|-----|------|
| t _{su(FS-CK)} | Setup time, FS low before next negative SCLK edge | 8 | | | ns |
| t _{su(C16-FS)} | Setup time, 16^{th} negative edge after FS low on which bit D0 is sampled before rising edge of FS. μC mode only | 10 | | | ns |
| t _{su(FS-C17)} | μC mode, setup time, FS high before 17 th negative edge of SCLK. | 10 | | | ns |
| t _{su(CK-FS)} | DSP mode, setup time, SLCK low before FS low. | 5 | | | ns |
| t _{wL(LDAC)} | LDAC duration low | 10 | | | ns |
| t _{wH} | SCLK pulse duration high | 16 | | | ns |
| t _{wL} | SCLK pulse duration low | 16 | | | ns |
| t _{su(FS-CK)} | Setup time, FS low before first negative SCLK edge | 8 | | | ns |
| t _{su(D)} | Setup time, data ready before SCLK falling edge | 8 | | | ns |
| t _{h(D)} | Hold time, data held valid after SCLK falling edge | 5 | | | ns |
| t _{wH(FS)} | FS duration high | 10 | | | ns |
| t _{wL(FS)} | FS duration low | 10 | | | ns |
| t _s | Settling time | See AC specs | | | |

⁽⁶⁾ Settling time is the time for the output signal to remain within ±0.5 LSB of the final measured value for a digital input code change of one count. The max time applies to code changes near zero scale or full scale. Assured by design; not tested.

⁽⁷⁾ Slew rate determines the time it takes for a change of the DAC output from 10% to 90% full-scale voltage.

⁽⁸⁾ Code transition: TLV5630 - 0x7FF to 0x800, TLV5631 - 0x7FCto 0x800, TLV5632 - 0x7F0 to 0x800.



TYPICAL CHARACTERISTICS

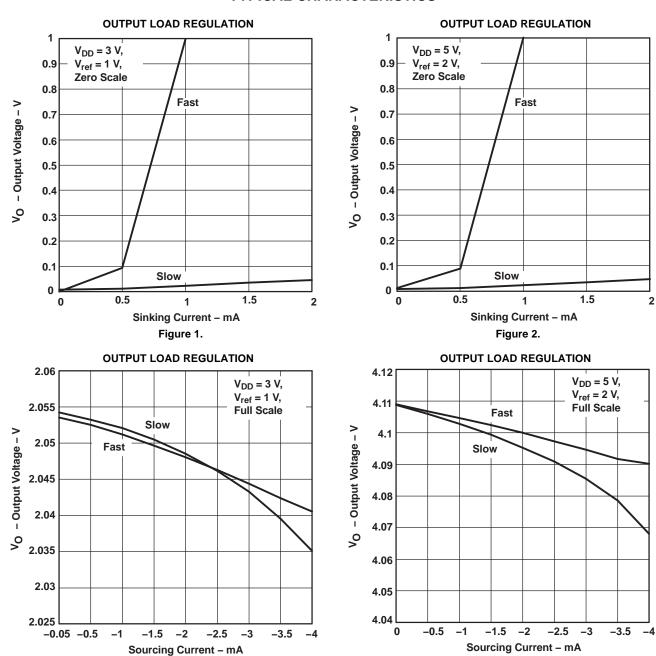
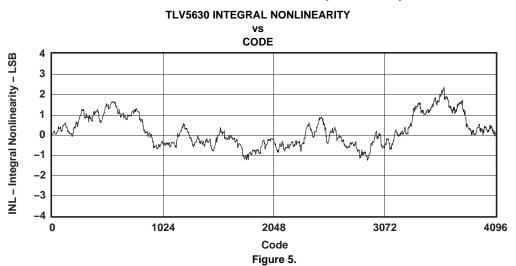


Figure 3.

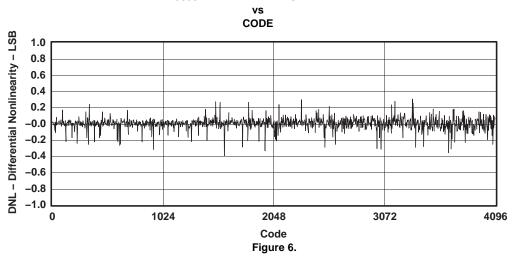
Figure 4.



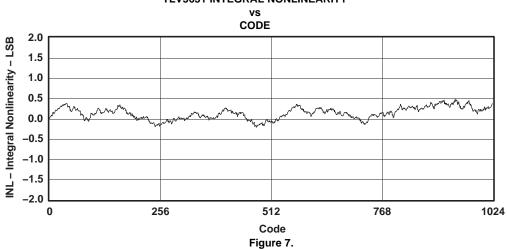
TYPICAL CHARACTERISTICS (continued)



TLV5630 DIFFERENTIAL NONLINEARITY



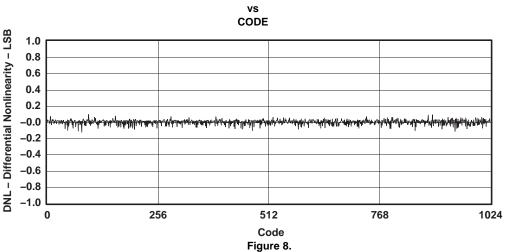
TLV5631 INTEGRAL NONLINEARITY



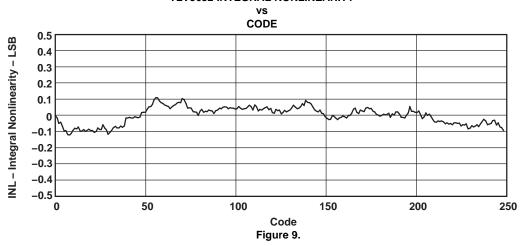


TYPICAL CHARACTERISTICS (continued)

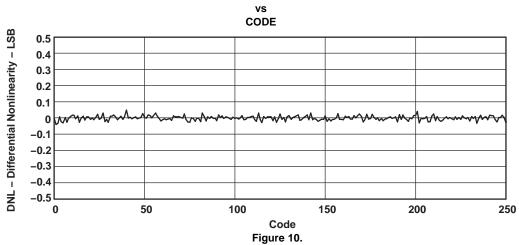
TLV5631 DIFFERENTIAL NONLINEARITY



TLV5632 INTEGRAL NONLINEARITY

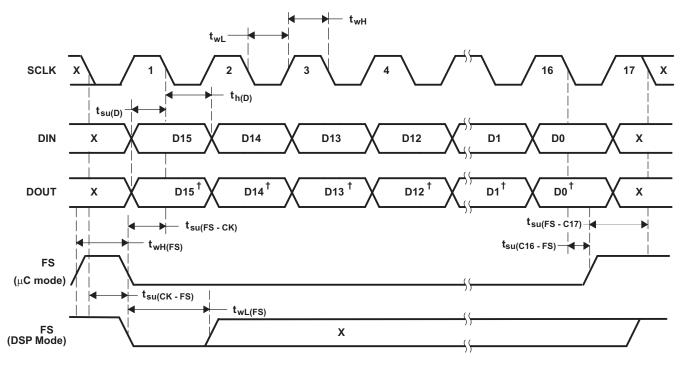


TLV5632 DIFFERENTIAL NONLINEARITY





PARAMETER MEASUREMENT INFORMATION



[†] Previous input data

Figure 11. Serial Interface Timing

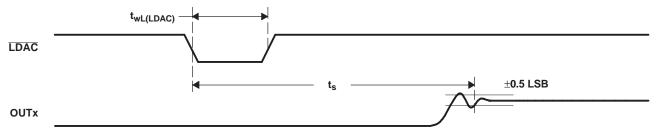


Figure 12. Output Timing



APPLICATION INFORMATION

GENERAL FUNCTION

The TLV5630/31/32 are 8-channel, single-supply DACs, based on a resistor string architecture. They consist of a serial interface, a speed and power-down control logic, an internal reference, a resistor string, and a rail-to-rail output buffer.

The output voltage (full scale determined by reference) for each channel is given by:

$$2REF \frac{CODE}{0x1000}[V]$$

where REF is the reference voltage and CODE is the digital input value. The input range is 0x000 to 0xFFF for the TLV5630, 0x000 to 0xFFC for the TLV5631, and 0x000 to 0xFF0 for the TLV5632.

POWER ON RESET (POR)

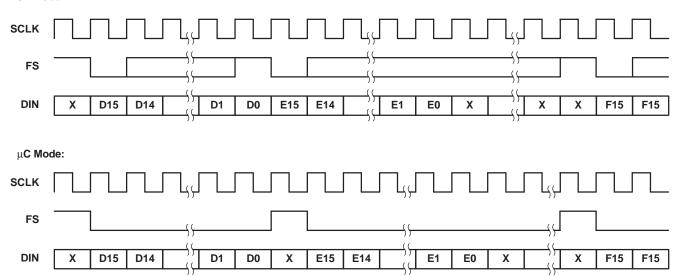
The built-in power-on-reset circuit controls the output voltage after power up. On <u>power</u> up, all latches including the preset register are set to zero, but the DAC outputs are only set to zero if the <u>LDAC</u> is low. The DAC outputs may have a small offset error produced by the output buffer. The registers remains at zero until a valid write sequence is made to the DAC, changing the DAC register data. This is useful in applications where it is important to know the state of the outputs of the DAC after power up. All digital inputs must be logic low until the digital and analog supplies are applied. Any logic high voltages applied to the logic input pins when power is not applied to AV_{DD} and DV_{DD} , may power the device logic circuit through the overvoltage protection diode causing an undesired operation. When separate analog (AV_{DD}) and digital (DV_{DD}) supplies are used, AV_{DD} must come up first before DV_{DD} , to ensure that the power-on-reset circuit operates correctly.

SERIAL INTERFACE

A falling edge of FS starts shifting the data on DIN starting with the MSB to the internal register on the falling edges of SCLK. After 16 bits have been transferred, the content of the shift register is moved to one of the DAC holding registers, depending on the address bits within the data word. A logic 0 on the LDAC pin is required to transfer the content of the DAC holding register to the DAC latch and to update the DAC outputs. LDAC is an asynchronous input. It can be held low if a simultaneous update of all eight channels is not needed.

For daisy-chaining, DOUT provides the data sampled on DIN with a delay of 16 clock cycles.







Difference between DSP mode (MODE = N.C. or 0) and μ C (MODE = 1) mode:

- In μC mode, FS needs to be held low until all 16 data bits have been transferred. If FS is driven high before the 16th falling clock edge, the data transfer is cancelled. The DAC is updated after a rising edge on FS.
- In DSP mode, FS needs to stay low for 20 ns and can go high before the 16th falling clock edge.
- In DSP mode there needs to be one falling SCLK edge before FS goes low to start the write (DIN) cycle. This
 extra falling SCLK edge has to happen at least 5 ns before FS goes low, t_{su(CK-FS)} ≥ 5 ns.
- In μC mode, the extra falling SCLK edge is not necessary. However, if it does happen, the extra negative SCLK edge is not allowed to occur within 10 ns after FS goes HIGH to finish the WRITE cycle (t_{su(FS-C17)}).

SERIAL CLOCK FREQUENCY AND UPDATE RATE

The maximum serial clock frequency is given by:

$$f_{sclkmax} = \frac{1}{t_{whmin} + t_{wlmin}} = 30 \text{ MHz}$$

The maximum update rate is:

$$f_{updatemax} = \frac{1}{16(t_{whmin} + t_{wlmin})} = 1.95 \text{ MHz}$$

Note, that the maximum update rate is just a theoretical value for the serial interface, as the settling time of the DAC has to be considered also.

DATA FORMAT

The 16-bit data word consists of two parts:

Address bits (D15...D12)

Data bits (D11...D0)

| D15 | D14 ` | D13 | D12 | D11 | D10 | D9 | D8 | D7 | D6 | D5 | D4 | D3 | D2 | D1 | D0 |
|-----|-------|-----|-----|-----|------|----|----|----|----|----|----|----|----|----|----|
| А3 | A2 | A1 | A0 | | Data | | | | | | | | | | |

Ax: Address bits. See table.

REGISTER MAP

| A3 | A2 | A1 | Α0 | FUNCTION |
|----|----|----|----|--------------------------|
| 0 | 0 | 0 | 0 | DAC A |
| 0 | 0 | 0 | 1 | DAC B |
| 0 | 0 | 1 | 0 | DAC C |
| 0 | 0 | 1 | 1 | DAC D |
| 0 | 1 | 0 | 0 | DAC E |
| 0 | 1 | 0 | 1 | DAC F |
| 0 | 1 | 1 | 0 | DAC G |
| 0 | 1 | 1 | 1 | DAC H |
| 1 | 0 | 0 | 0 | CTRL0 |
| 1 | 0 | 0 | 1 | CTRL1 |
| 1 | 0 | 1 | 0 | Preset |
| 1 | 0 | 1 | 1 | Reserved |
| 1 | 1 | 0 | 0 | DAC A and \overline{B} |
| 1 | 1 | 0 | 1 | DAC C and \overline{D} |
| 1 | 1 | 1 | 0 | DAC E and F |
| 1 | 1 | 1 | 1 | DAC G and H |



DAC A-H AND TWO-CHANNEL REGISTERS

Writing to DAC A-H sets the output voltage of channel A-H. It is possible to automatically generate the complement of one channel by writing to one of the four two-channel registers (DAC A and \overline{B} etc.).

The TLV5630 decodes all 12 data bits. The TLV5631 decodes D11 to D2 (D1 and D0 are ignored). The TLV5632 decodes D11 to D4 (D3 to D0 are ignored).

PRESET

The outputs of the DAC channels can be driven simultaneously to a predefined value stored in the preset register by driving the PRE input pin low and asserting the LDAC input pin. The preset register is cleared (set to zero) by the POR circuit after power up. Therefore, it must be written with a predefined value before asserting the PRE pin low, unless zero is the desired preset value. The PRE input is asynchronous to the clock.

CTRL0

| BIT | D11 | D10 | D9 | D8 | D7 | D6 | D5 | D4 | D3 | D2 | D1 | D0 |
|----------|-----|-----|----|----|----|----|----|----|----|----|----|----|
| Function | Χ | Χ | Χ | Χ | Χ | Х | X | PD | DO | R1 | R0 | IM |
| Default | Χ | Χ | Χ | Χ | Х | Х | Χ | 0 | 0 | 0 | 0 | 0 |

PD : Full device power down 0 = normal 1 = power down

DO : DOUT enable 0 = disabled 1 = enabled

R1:0 : Reference select bits 0 = external 1 = external, 2 = internal 1 V, 3 = internal 2 V

IM : Input mode $0 = \text{straight binary} \quad 1 = \text{twos complement}$

X : Reserved

If DOUT is enabled, the data input on DIN is output on DOUT with a 16-cycle delay. That makes it possible to daisy-chain multiple DACs on one serial bus.

CTRL1

| BIT | D11 | D10 | D9 | D8 | D7 | D6 | D5 | D4 | D3 | D2 | D1 | D0 |
|----------|-----|-----|----|----|----------|-----------------|-----------------|-----------------|-----------------|-----------------|-----------------|-----------------|
| Function | X | X | X | Х | P_{GH} | P _{EF} | P _{CD} | P _{AB} | S _{GH} | S _{EF} | S _{CD} | S _{AB} |
| Default | X | X | Х | Х | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 |

 P_{XY} : Power Down DAC_{XY} 0 = normal 1 = power down

 S_{XY} : Speed DAC_{XY} 0 = slow 1 = fast

XY : DAC pair AB, CD, EF or GH

In power-down mode, the amplifiers of the selected DAC pair are disabled and the total power consumption of the device is significantly reduced. Power-down mode of a specific DAC pair can be selected by setting the P_{XY} bit within the data word to 1.

There are two settling time modes: fast and slow. Fast mode of a DAC pair is selected by setting S_{XY} to 1 and slow mode is selected by setting S_{XY} to 0.



REFERENCE

The DAC reference can be sourced internally or externally by programming bits D2 (R1) and D1 (R0) of the CTRL0 register (address = 08h). If an external source of reference is applied to the REF pin, the device must be configured to accept the external reference source by setting R1 and R0 to 00 or 01. If R1 and R0 is set to select for internal reference, a voltage of 1.024 V (if R1 and R0 = 10) or 2.048 V (if R1 and R0 = 11) is available. The internal reference can source up to 1 mA, therefore, it can be used as an external system reference. A decoupling capacitor must be connected to the REF pin if internal reference is selected to ensure output stability. A 1 μ F to 10 μ F capacitor in parallel to a 100 μ F capacitor should be sufficient, see Figure 13.

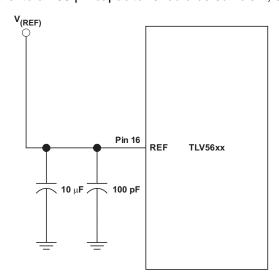


Figure 13. Reference Pin Decoupling Connection

BUFFERED AMPLIFIER

The DAC outputs are buffered by an amplifier with a gain of two, which are configurable as Class A (fast mode) or Class AB (slow or low-power mode). The output buffers have near rail-to-rail output with short-circuit protection, and can reliably drive a $2-k\Omega$ load with a 100-pF load capacitance.

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PACKAGING INFORMATION

| Orderable Device | Status | Package Type | Package Drawing | Pins | Package Qty | Eco Plan | Lead finish/ Ball material | MSL Peak Temp | Op Temp (°C) | Device Marking (4/5) | Samples |
|------------------|--------|--------------|--------------------|------|----------------|--------------|-------------------------------|--------------------|--------------|-------------------------|---------|
| TLV5630IDW | ACTIVE | SOIC | DW | 20 | 25 | RoHS & Green | NIPDAU | Level-1-260C-UNLIM | -40 to 85 | TLV5630I | Samples |
| TLV5630IPW | ACTIVE | TSSOP | PW | 20 | 70 | RoHS & Green | NIPDAU | Level-1-260C-UNLIM | -40 to 85 | TY5630 | Samples |
| TLV5630IPWG4 | ACTIVE | TSSOP | PW | 20 | 70 | RoHS & Green | NIPDAU | Level-1-260C-UNLIM | -40 to 85 | TY5630 | Samples |
| TLV5630IPWR | ACTIVE | TSSOP | PW | 20 | 2000 | RoHS & Green | NIPDAU | Level-1-260C-UNLIM | -40 to 85 | TY5630 | Samples |
| TLV5631IDW | ACTIVE | SOIC | DW | 20 | 25 | RoHS & Green | NIPDAU | Level-1-260C-UNLIM | -40 to 85 | TLV5631I | Samples |
| TLV5631IDWG4 | ACTIVE | SOIC | DW | 20 | 25 | RoHS & Green | NIPDAU | Level-1-260C-UNLIM | -40 to 85 | TLV5631I | Samples |
| TLV5631IDWR | ACTIVE | SOIC | DW | 20 | 2000 | RoHS & Green | NIPDAU | Level-1-260C-UNLIM | -40 to 85 | TLV5631I | Samples |
| TLV5631IPW | ACTIVE | TSSOP | PW | 20 | 70 | RoHS & Green | NIPDAU | Level-1-260C-UNLIM | -40 to 85 | TY5631 | Samples |
| TLV5631IPWG4 | ACTIVE | TSSOP | PW | 20 | 70 | RoHS & Green | NIPDAU | Level-1-260C-UNLIM | -40 to 85 | TY5631 | Samples |
| TLV5631IPWR | ACTIVE | TSSOP | PW | 20 | 2000 | RoHS & Green | NIPDAU | Level-1-260C-UNLIM | -40 to 85 | TY5631 | Samples |
| TLV5631IPWRG4 | ACTIVE | TSSOP | PW | 20 | 2000 | RoHS & Green | NIPDAU | Level-1-260C-UNLIM | -40 to 85 | TY5631 | Samples |
| TLV5632IDW | ACTIVE | SOIC | DW | 20 | 25 | RoHS & Green | NIPDAU | Level-1-260C-UNLIM | -40 to 85 | TLV5632I | Samples |
| TLV5632IDWR | ACTIVE | SOIC | DW | 20 | 2000 | RoHS & Green | NIPDAU | Level-1-260C-UNLIM | -40 to 85 | TLV5632I | Samples |
| TLV5632IPW | ACTIVE | TSSOP | PW | 20 | 70 | RoHS & Green | NIPDAU | Level-1-260C-UNLIM | -40 to 85 | TY5632 | Samples |
| TLV5632IPWR | ACTIVE | TSSOP | PW | 20 | 2000 | RoHS & Green | NIPDAU | Level-1-260C-UNLIM | -40 to 85 | TY5632 | Samples |

⁽¹⁾ The marketing status values are defined as follows: **ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.



PACKAGE OPTION ADDENDUM

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(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





| A0 | Dimension designed to accommodate the component width |
|----|---|
| В0 | Dimension designed to accommodate the component length |
| K0 | Dimension designed to accommodate the component thickness |
| W | Overall width of the carrier tape |
| P1 | Pitch between successive cavity centers |

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

| Device | Package Type | Package Drawing | | SPQ | Reel Diameter (mm) | Reel Width W1 (mm) | A0 (mm) | B0 (mm) | K0 (mm) | P1 (mm) | W (mm) | Pin1 Quadrant |
|-------------|-----------------|--------------------|----|------|--------------------------|--------------------------|------------|------------|------------|------------|-----------|------------------|
| TLV5630IPWR | TSSOP | PW | 20 | 2000 | 330.0 | 16.4 | 6.95 | 7.1 | 1.6 | 8.0 | 16.0 | Q1 |
| TLV5631IDWR | SOIC | DW | 20 | 2000 | 330.0 | 24.4 | 10.8 | 13.3 | 2.7 | 12.0 | 24.0 | Q1 |
| TLV5631IPWR | TSSOP | PW | 20 | 2000 | 330.0 | 16.4 | 6.95 | 7.1 | 1.6 | 8.0 | 16.0 | Q1 |
| TLV5632IDWR | SOIC | DW | 20 | 2000 | 330.0 | 24.4 | 10.8 | 13.3 | 2.7 | 12.0 | 24.0 | Q1 |
| TLV5632IPWR | TSSOP | PW | 20 | 2000 | 330.0 | 16.4 | 6.95 | 7.1 | 1.6 | 8.0 | 16.0 | Q1 |



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*All dimensions are nominal

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|---------------------------------|--------------|-----------------|------|------|-------------|------------|-------------|
| Device | Package Type | Package Drawing | Pins | SPQ | Length (mm) | Width (mm) | Height (mm) |
| TLV5630IPWR | TSSOP | PW | 20 | 2000 | 350.0 | 350.0 | 43.0 |
| TLV5631IDWR | SOIC | DW | 20 | 2000 | 350.0 | 350.0 | 43.0 |
| TLV5631IPWR | TSSOP | PW | 20 | 2000 | 350.0 | 350.0 | 43.0 |
| TLV5632IDWR | SOIC | DW | 20 | 2000 | 350.0 | 350.0 | 43.0 |
| TLV5632IPWR | TSSOP | PW | 20 | 2000 | 350.0 | 350.0 | 43.0 |

PACKAGE MATERIALS INFORMATION

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TUBE



*All dimensions are nominal

| Device | Package Name | Package Type | Pins | SPQ | L (mm) | W (mm) | T (µm) | B (mm) |
|--------------|--------------|--------------|------|-----|--------|--------|--------|--------|
| TLV5630IDW | DW | SOIC | 20 | 25 | 506.98 | 12.7 | 4826 | 6.6 |
| TLV5630IPW | PW | TSSOP | 20 | 70 | 530 | 10.2 | 3600 | 3.5 |
| TLV5630IPWG4 | PW | TSSOP | 20 | 70 | 530 | 10.2 | 3600 | 3.5 |
| TLV5631IDW | DW | SOIC | 20 | 25 | 506.98 | 12.7 | 4826 | 6.6 |
| TLV5631IDWG4 | DW | SOIC | 20 | 25 | 506.98 | 12.7 | 4826 | 6.6 |
| TLV5631IPW | PW | TSSOP | 20 | 70 | 530 | 10.2 | 3600 | 3.5 |
| TLV5631IPWG4 | PW | TSSOP | 20 | 70 | 530 | 10.2 | 3600 | 3.5 |
| TLV5632IDW | DW | SOIC | 20 | 25 | 506.98 | 12.7 | 4826 | 6.6 |
| TLV5632IPW | PW | TSSOP | 20 | 70 | 530 | 10.2 | 3600 | 3.5 |



SOIC



NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.



SOIC



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOIC



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





SMALL OUTLINE PACKAGE



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



PW (R-PDSO-G20)

PLASTIC SMALL OUTLINE



NOTES:

- All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
 C. Publication IPC-7351 is recommended for alternate design.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



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